Unit: mm

TOSHIBA Field Effect Transistor Silicon P Channel MOS Type ( $L^2$ - $\pi$ -MOSV)

# 2SJ507

# Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4 V gate drive

• Low drain–source ON resistance :  $R_{DS (ON)} = 0.5 \Omega \text{ (typ.)}$ • High forward transfer admittance :  $|Y_{fs}| = 1.0 \text{ S (typ.)}$ • Low leakage current :  $I_{DSS} = -100 \mu A \text{ (max) (V}_{DS} = -60 \text{ V)}$ 

• Enhancement-mode :  $V_{th} = -0.8 \sim -2.0 \text{ V (V}_{DS} = -10 \text{ V, I}_{D} = -1 \text{ mA)}$ 

## **Maximum Ratings (Ta = 25°C)**

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		$V_{DSS}$	-60	V	
Drain-gate voltage (Ro	<sub>SS</sub> = 20 kΩ)	$V_{DGR}$	-60	V	
Gate-source voltage		V <sub>GSS</sub>	±20	V	
Drain current	DC (Note 1)	ΙD	-1	Α	
	Pulse (Note 1)	$I_{DP}$	-3	Α	
Drain power dissipation	١	$P_{D}$	0.9	W	
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	249.6	mJ	
Avalanche current		I <sub>AR</sub>	-1	Α	
Repetitive avalanche e	nergy (Note 3)	E <sub>AR</sub>	0.09	mJ	
Channel temperature		T <sub>ch</sub>	150	°C	
Storage temperature ra	ange	T <sub>stg</sub>	-55~150	°C	

# 5.1 max 0.75 max 1.0 max 0.8 max 1.27 2.54 1 2 3 1.SOURCE 2.DRAIN 3.GATE JEDEC TO-92MOD JEITA — TOSHIBA 2-5J1C

Weight: 0.36 g (typ.)

### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	138	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C

Note 2:  $V_{DD}$  = -25 V,  $T_{ch}$  = 25°C (initial), L = 339 mH,  $R_G$  = 25  $\Omega$ ,  $I_{AR}$  = -1 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.

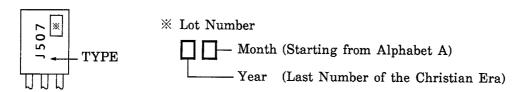
# **Electrical Characteristics (Ta = 25°C)**

Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±16 V, V <sub>DS</sub> = 0 V	_	_	±10	μΑ
Drain cut-off cur	rent	I <sub>DSS</sub>	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V	_	_	-100	μΑ
Drain-source brovoltage	eakdown	V <sub>(BR) DSS</sub>	$I_D = -10$ mA, $V_{GS} = 0$ V	-60	_	1	٧
Gate threshold v	roltage	$V_{th}$	$V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA}$	-0.8	_	-2.0	V
Duein acumes ON resistants		R <sub>DS (ON)</sub>	$V_{GS} = -4 \text{ V}, I_D = -0.5 \text{ A}$		0.72	1.0	Ω
Drain-source ON resistance	$V_{GS} = -10 \text{ V}, I_D = -0.5 \text{ A}$		_	0.5	0.7		
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = -10 V, I <sub>D</sub> = -0.5 A	0.5	1.0	_	S
Input capacitanc	е	C <sub>iss</sub>		_	170	_	
Reverse transfer capacitance Output capacitance		C <sub>rss</sub>	V <sub>DS</sub> = -10 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	25	_	pF
		Coss		-	72	_	
Switching time	Rise time	t <sub>r</sub>	$V_{GS} = 10V$ $V_{DD} = -0.5A$ $V_{DUT}$ $R_{L} = 60\Omega$ $V_{DD} = -30V$ $Duty \le 1\%, \ t_{W} = 10 \mu s$	_	20	_	
	Turn-on time	t <sub>on</sub>		_	35	_	20
	Fall time	t <sub>f</sub>		_	30	_	ns
	Turn-off time	t <sub>off</sub>		_	135	_	
Total gate charplus gate-drain)	Total gate charge (Gate-source plus gate-drain) $Q_g$ $V_{DD} \approx -48 \text{ V, } V_{GS} = -10 \text{ V,}$		_	5.6	_	_	
Gate-source charge		Q <sub>gs</sub>	I <sub>D</sub> = -1 A		3.9	_	nC -
Gate-drain ("miller") charge		$Q_{gd}$			1.7	_	

# **Source-Drain Ratings and Characteristics (Ta = 25°C)**

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	_	-1	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	-3	А
Forward voltage (diode)	$V_{DSF}$	$I_{DR} = -1 \text{ A, } V_{GS} = 0 \text{ V}$	1	1	1.5	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = -1 A, V <sub>GS</sub> = 0 V dI <sub>DR</sub> / dt = 50 A / μs	1	58	1	ns
Reverse recovery charge	$Q_{rr}$			72.5	_	nC

# Marking



2 2002-09-04

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